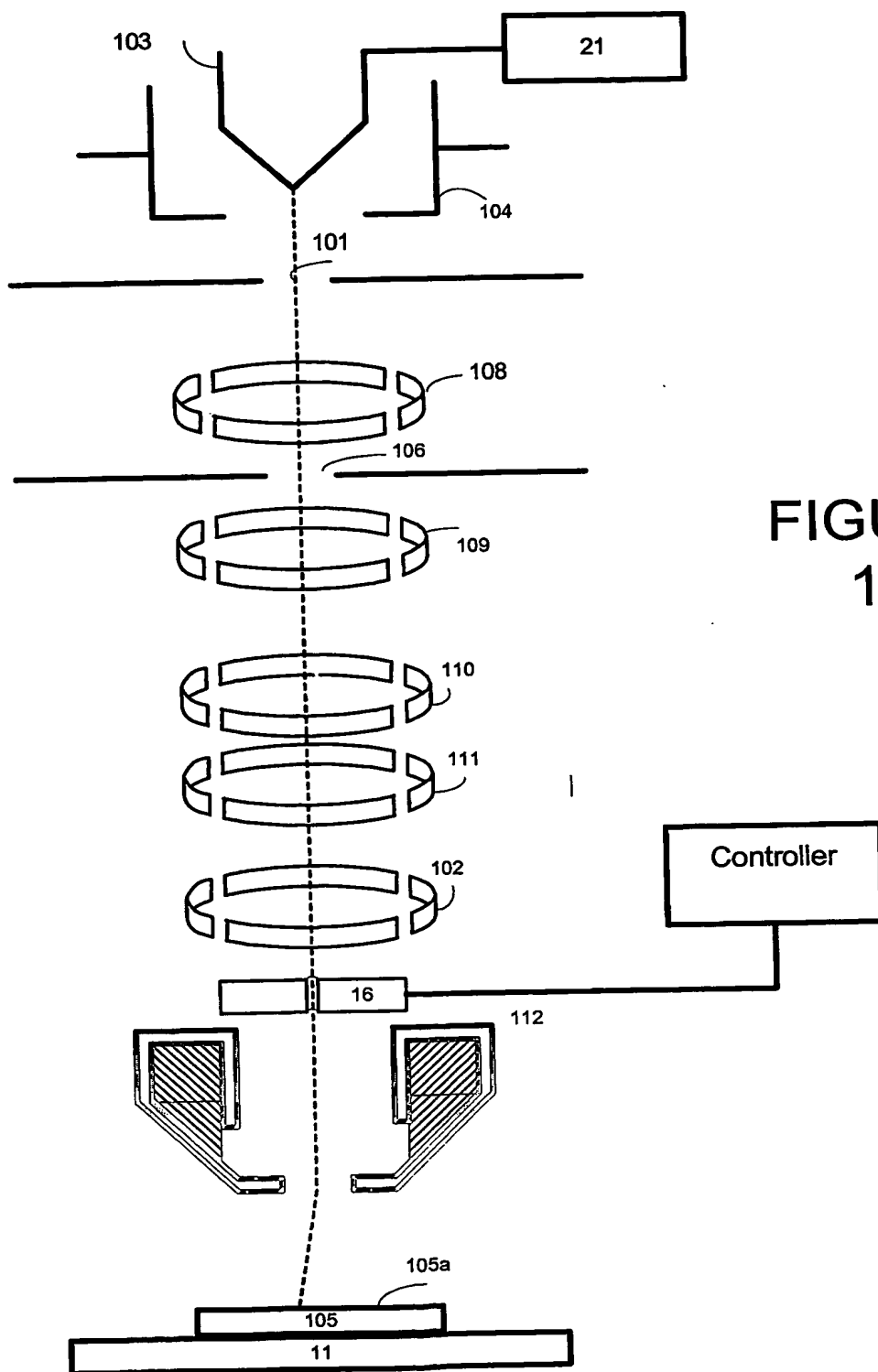


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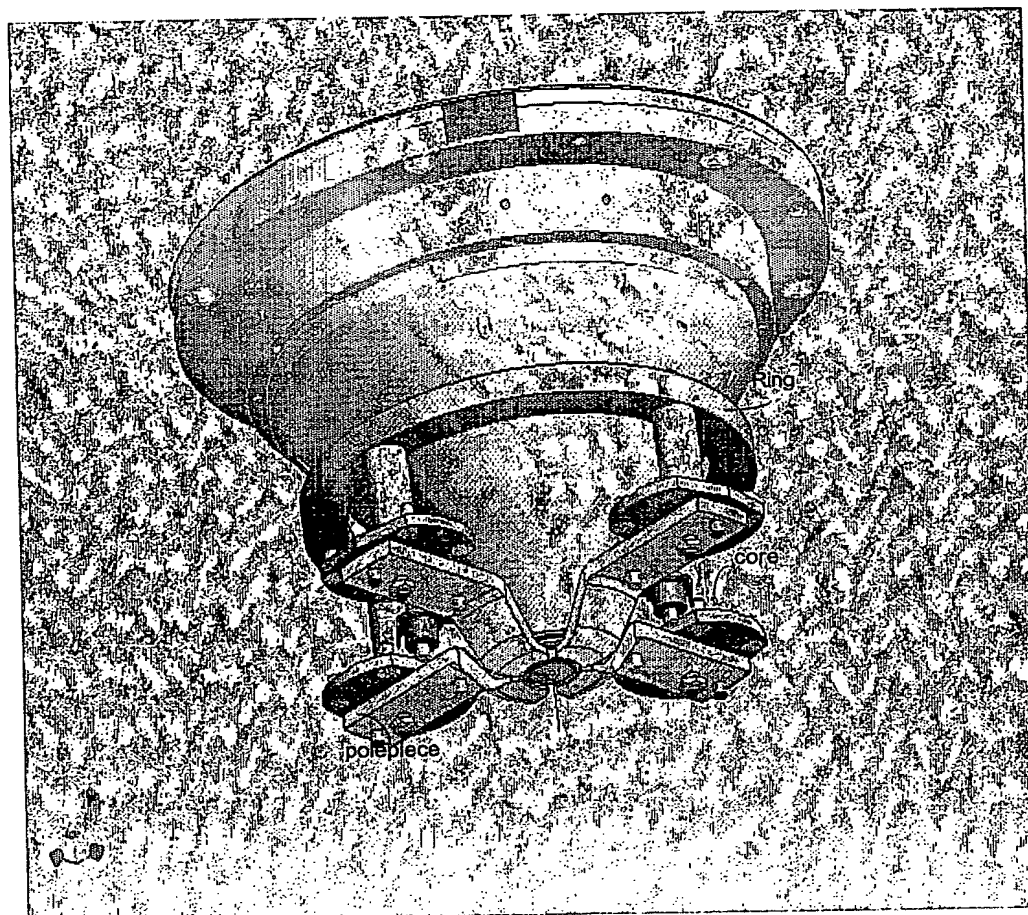
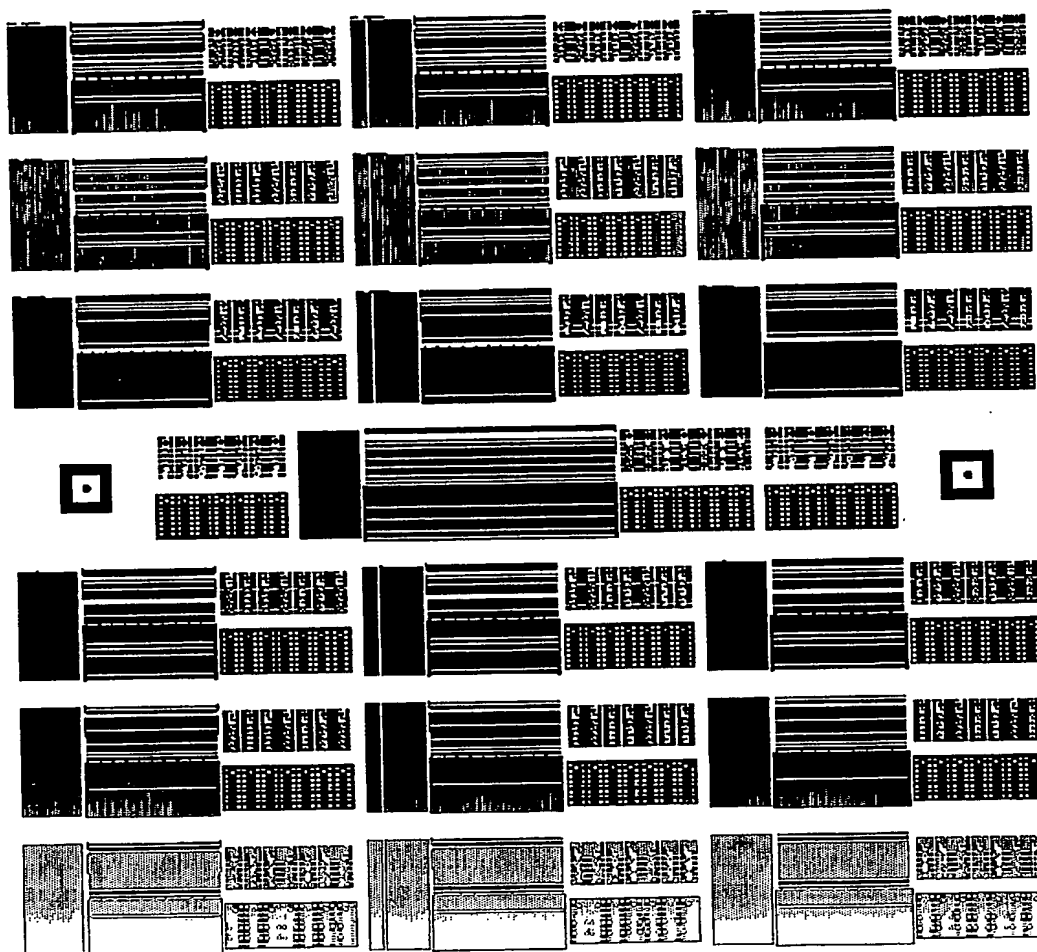


FIGURE 1b

FIGURE 2



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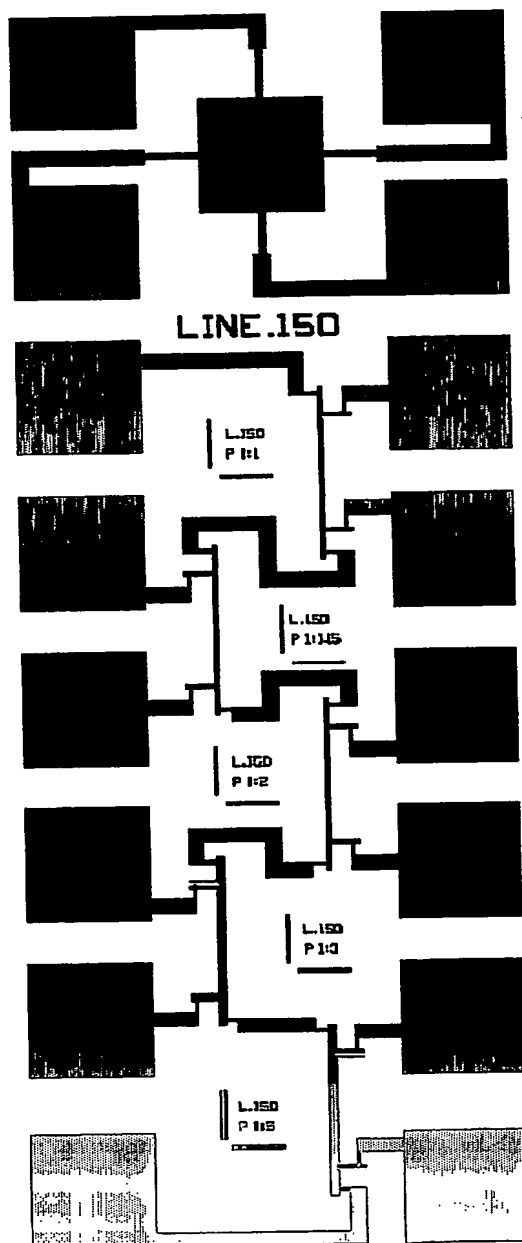


FIGURE 3

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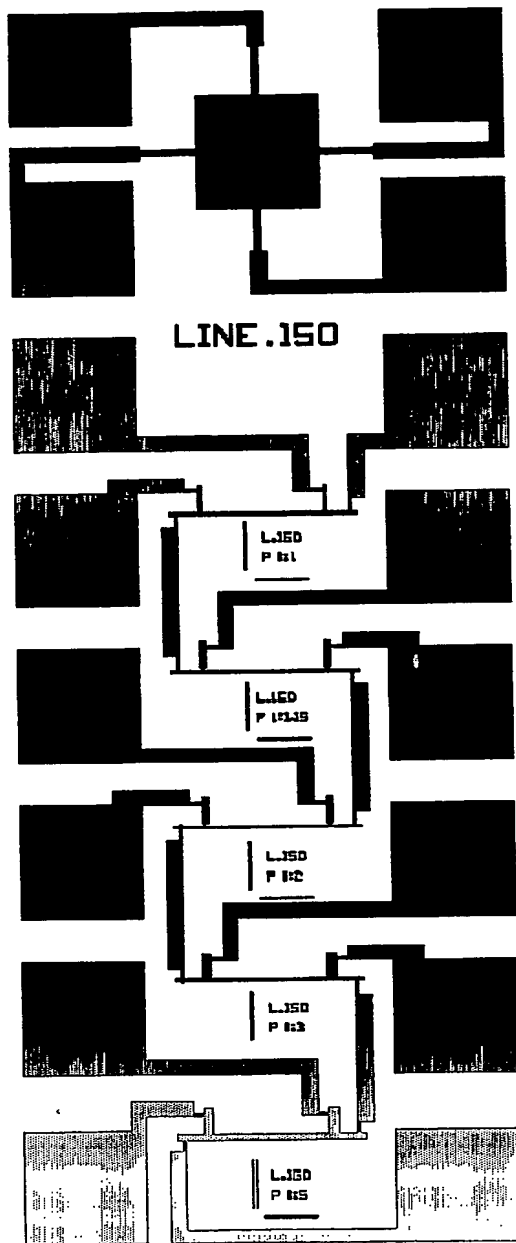


FIGURE 4

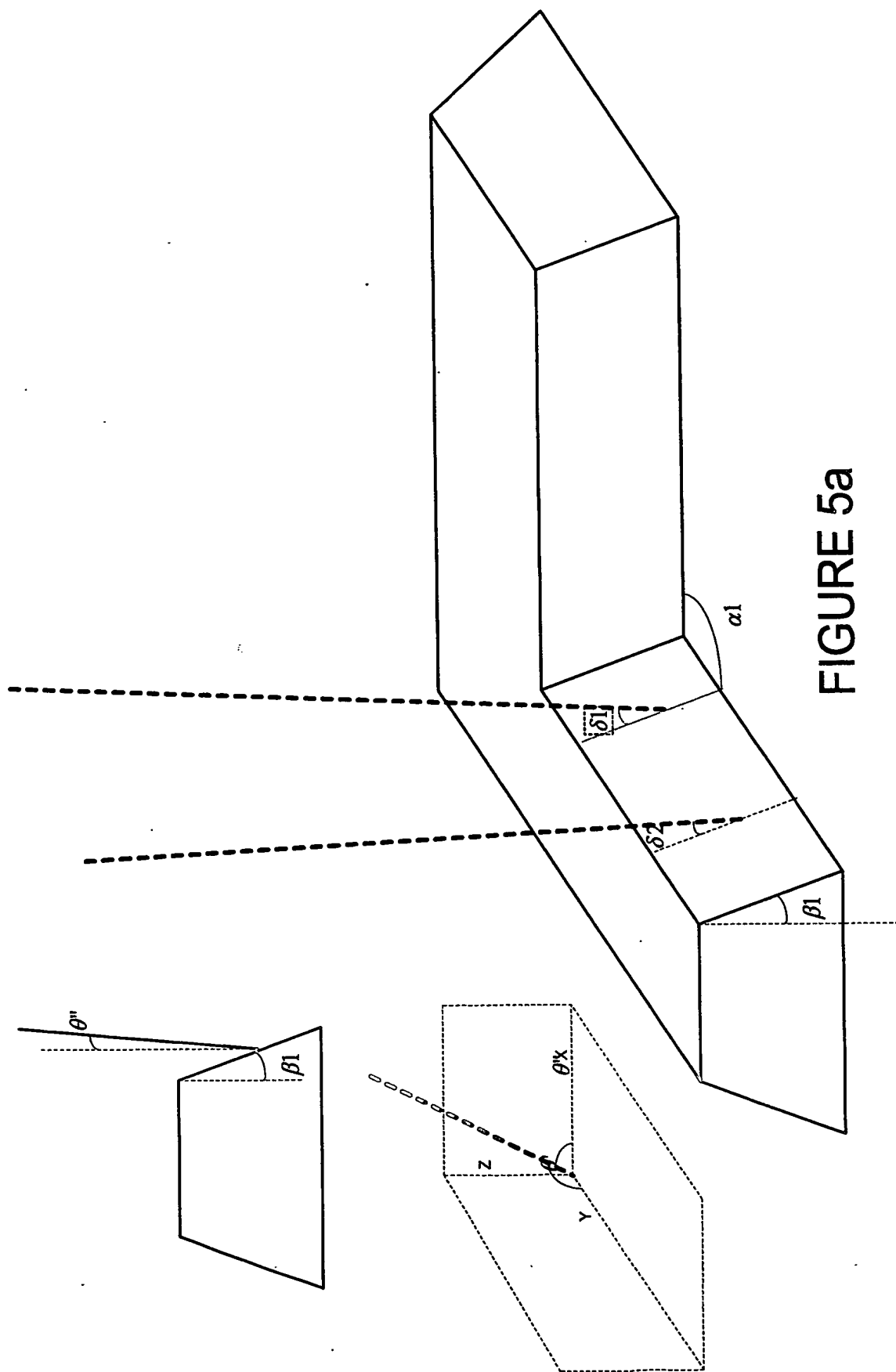


FIGURE 5a

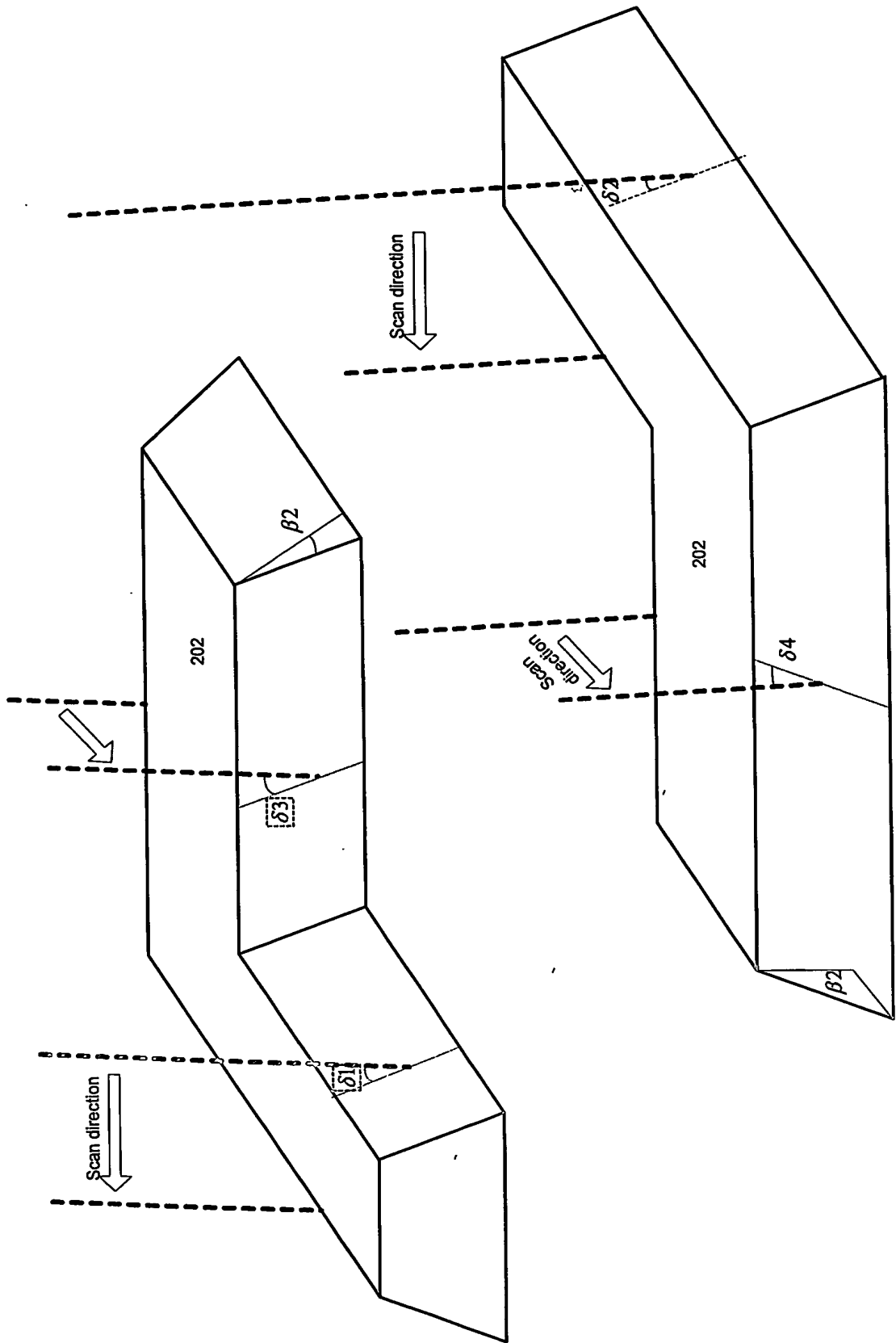


FIGURE 5b

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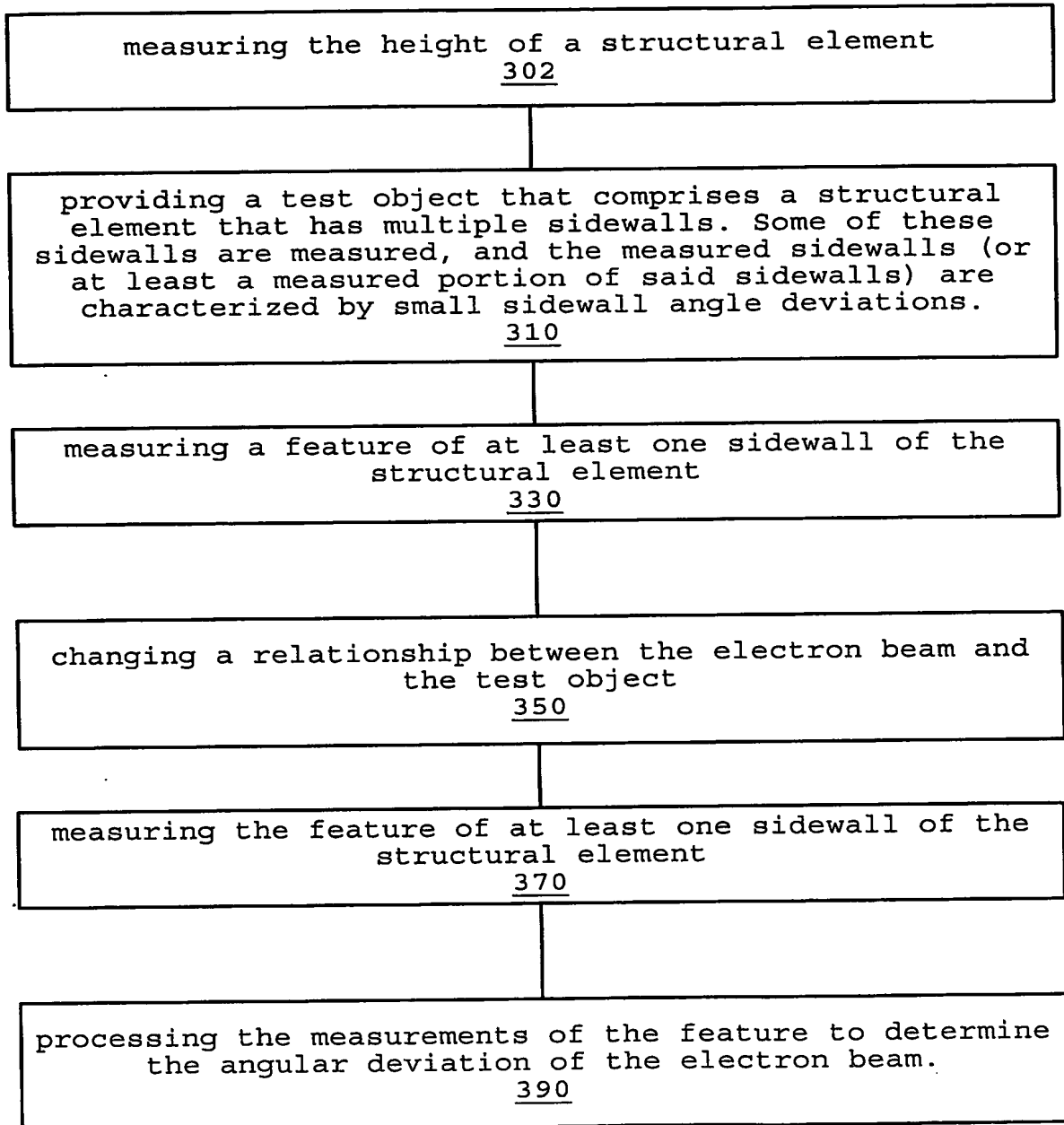
300

FIGURE 6

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providing a test object that includes a first and a second structural elements; whereas the first structural element has a first sidewall that is oriented at a first sidewall angle β_1 ; whereas the second structural element had a second sidewall that is oriented at a second sidewall angle β_2

410

measuring a feature of the first sidewall by scanning the first sidewall with an electron beam whereas the angular orientation between the electron beam and the first sidewall is greater than β_1

430

measuring a feature of the second sidewall by scanning the second sidewall with an electron beam whereas the angular orientation between the electron beam and the second sidewall is greater than β_2

450

measuring a feature of the first sidewall by scanning the first sidewall with an electron beam whereas the angular orientation between the electron beam and the first sidewall is smaller than β_1

470

measuring a feature of the second sidewall by scanning the first sidewall with an electron beam whereas the angular orientation between the electron beam and the second sidewall is smaller than β_2

490

determining the angular deviation in response to the measurements

495400

FIGURE 7

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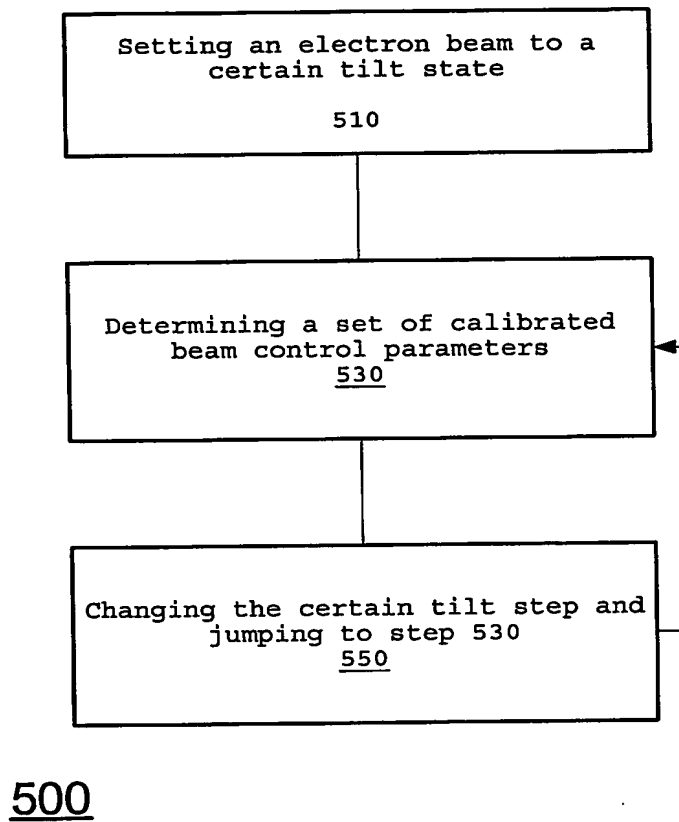


FIGURE 8

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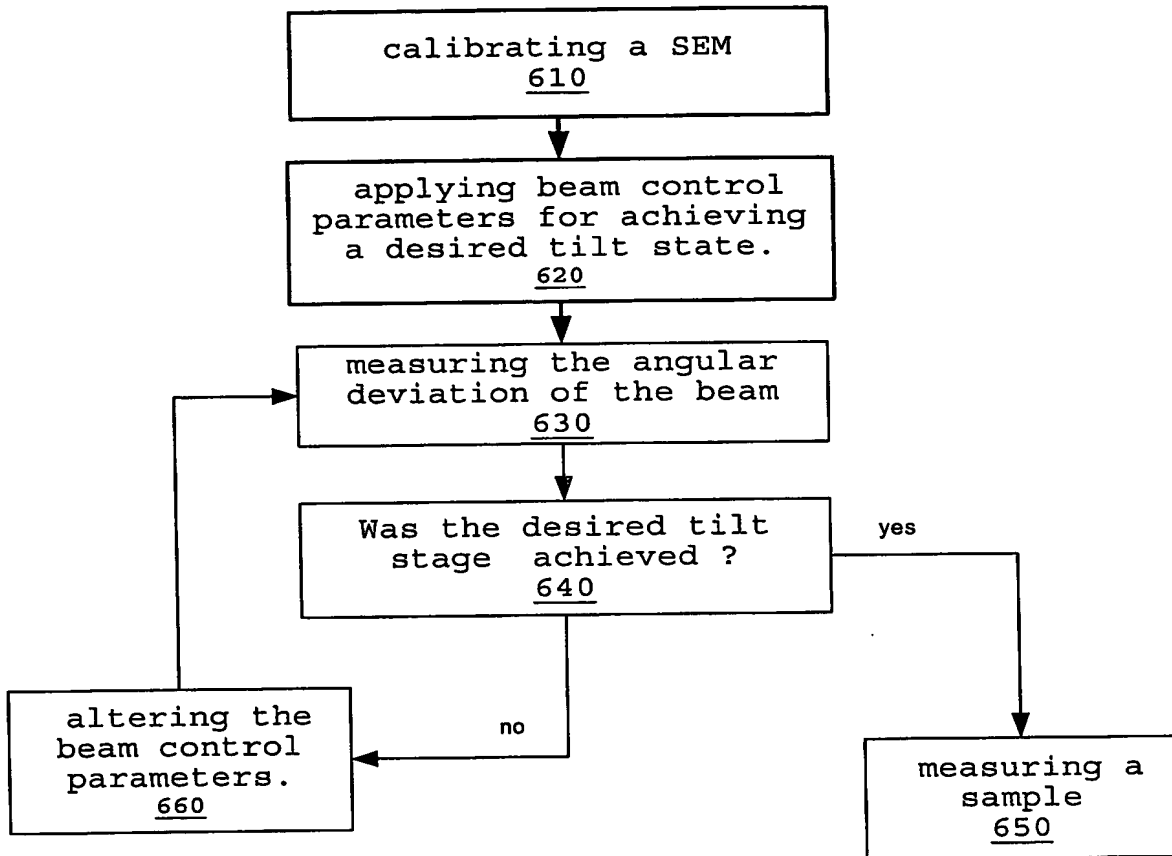
600

FIGURE 9

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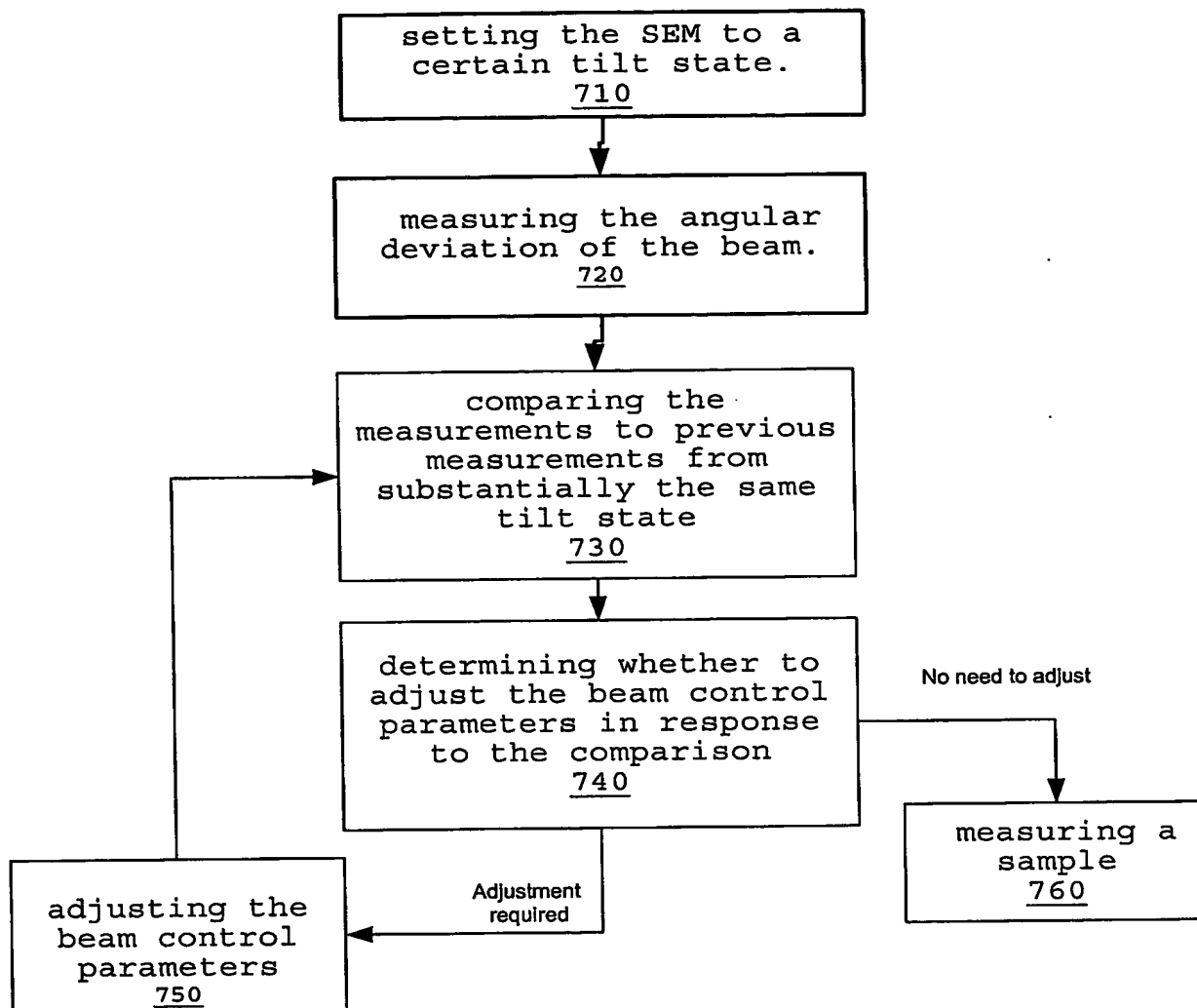


FIGURE 10